

**Notice of References Cited**

Application/Control No.

09/740,184

Applicant(s)/Patent Under

Reexamination

CHERUKURI, RAVIKRISHNA

Examiner

Van Kim T. Nguyen

Art Unit

2661

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,760,255	07-2004	Conley et al.	365/185.11
	B	US-6,567,900	05-2003	Kessler, Richard E.	711/157
	C	US-6,542,956	04-2003	Lee et al.	711/103
	D	US-6,507,885	01-2003	Lakhani et al.	711/5
	E	US-6,504,785	01-2003	Rao, G. R. Mohan	365/230.05
	F	US-6,446,181	09-2002	Ramagopal et al.	711/168
	G	US-6,415,350	07-2002	Asoh, Izumi	711/103
	H	US-6,381,239	04-2002	Atkinson et al.	370/362
	I	US-6,373,849	04-2002	Noonan, Michael E.	370/408
	J	US-5,860,083	01-1999	Sukegawa, Hiroshi	711/103
	K	US-5,729,717	03-1998	Tamada et al.	711/164
	L	US-5,659,695	08-1997	Kelley et al.	711/5
	M	US-5,175,842	12-1992	Totani, Tokuyuki	711/161

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.